

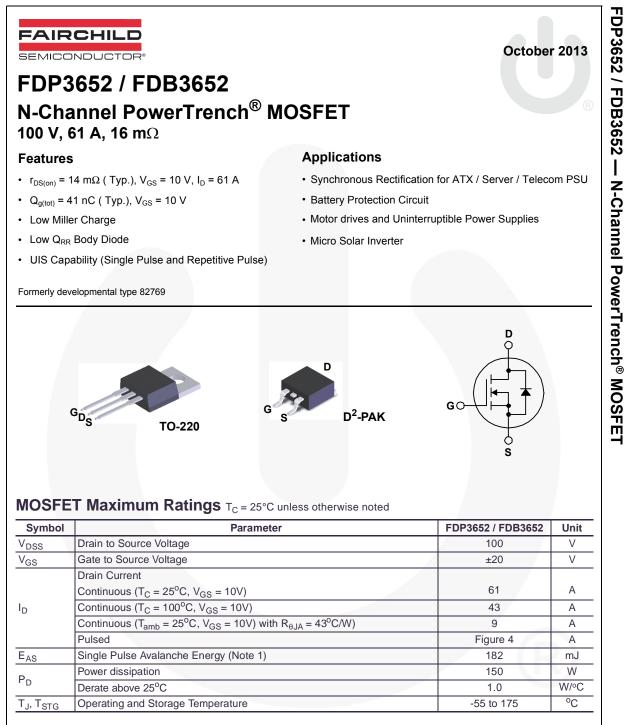
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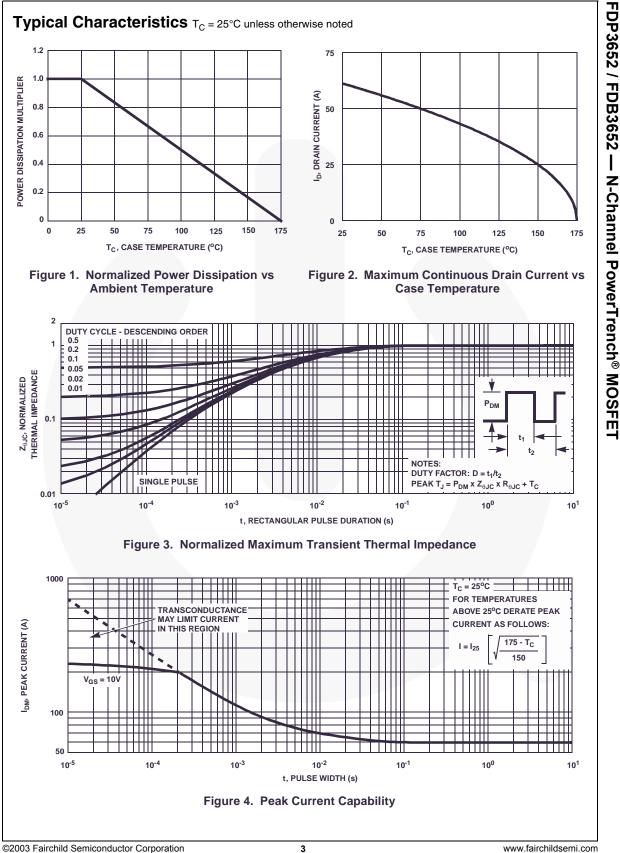
Thermal Characteristics

$R_{ extsf{ heta}JC}$	Thermal Resistance Junction to Case TO-220, D ² -PAK	1.0	°C/W
R_{\thetaJA}	Thermal Resistance Junction to Ambient TO-220, D2-PAK (Note 2)	62	°C/W
R_{\thetaJA}	Thermal Resistance Junction to Ambient D ² -PAK, 1in ² copper pad area	43	°C/W

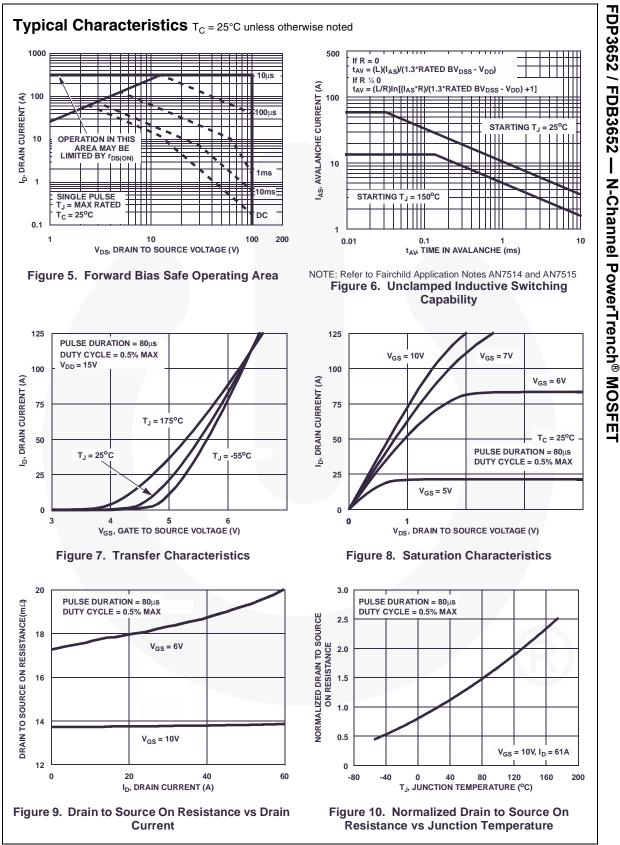
Device Marking FDB3652		Device	Package D ² -PAK	Reel Size 330 mm	Tape Width 24 mm		Quantity 800 units	
		FDB3652						
FDF	P3652	FDP3652	TO-220	Tube	N/A		50 units	
Electric	cal Char	acteristics T _C = 25°C	unless otherwise	e noted				
Symbol		Parameter	Test C	Conditions	Min	Тур	Мах	Units
Off Char	acteristic	s						
B _{VDSS}		ource Breakdown Voltage	$l_{p} = 250 \mu A$	$v_{\alpha\alpha} = 0 V$	100	-	-	V
-1055			$I_D = 250\mu A, V_{GS} = 0V$ $V_{DS} = 80V$		-	-	1	
I _{DSS}	Zero Gate Voltage Drain Current		$V_{GS} = 0V$ $T_C = 150^{\circ}C$		-	-	250	μA
I _{GSS}	Gate to S	ource Leakage Current	$V_{GS} = \pm 20V$		-	-	±100	nA
	I		00		1	1	1	
	acteristic							
V _{GS(TH)}	Gate to Se	ource Threshold Voltage	$V_{GS} = V_{DS}, I_{E}$		2	-	4	V
r _{DS(ON)}			$I_{\rm D} = 61 {\rm A}, {\rm V}_{\rm GS}$		-	0.014	0.016	
	Drain to S	ource On Resistance	$I_D = 30A, V_{GS}$		-	0.018	0.026	Ω
			$I_{\rm D} = 61A, V_{\rm GS}$	₃ = 10V,	-	0.035	0.043	
			T _J = 175 ^o C					
Dynamic	Characte	eristics						
C _{ISS}	Input Cap	acitance			-	2880	-	pF
C _{OSS}	Output Ca	apacitance	──V _{DS} = 25V, V ──f = 1MHz	GS = 0V,	-	390	-	pF
C _{RSS}	Reverse T	Fransfer Capacitance			-	100	-	pF
Q _{g(TOT)}	Total Gate	e Charge at 10V	$V_{GS} = 0V$ to 1			41	53	nC
Q _{g(TH)}	Threshold	I Gate Charge	$V_{GS} = 0V$ to 2	$V V_{DD} = 50V$	-	5	6.5	nC
Q _{gs}	Gate to Se	ource Gate Charge		$I_D = 61A$	-	15	-	nC
Q _{gs2}		rge Threshold to Plateau		$I_g = 1.0 \text{mA}$	-	10	-	nC
Q _{gd}	Gate to D	rain "Miller" Charge			-	10	-	nC
Switchin	o Charac	teristics (V _{GS} = 10V)						
t _{ON}	Turn-On T					-	146	ns
t _{d(ON)}		Delay Time	-	$V_{DD} = 50V, I_D = 61A$ $V_{GS} = 10V, R_{GS} = 6.8\Omega$		12	-	ns
t _r	Rise Time	,	Vpp = 50V. lp			85	-	ns
t _{d(OFF)}	Turn-Off D	Delay Time				26	-	ns
t _f	Fall Time					45		ns
t _{OFF}	Turn-Off T	ime			-	-	107	ns
	Di				•	•		
Drain-Sc	burce Diod	de Characteristics			1			\sim
V _{SD}	Source to Drain Diode Voltage		I _{SD} = 61A		-	-	1.25	V
			I _{SD} = 30A	(), , , , , , , , , , , , , , , , , , ,	-	-	1.0	V
. 30	Reverse F	Recovery Time	$I_{SD} = 61A$, $dI_{SD}/dt = 100A/\mu s$		-	-	62 45	ns
t _{rr} Q _{RR}		Recovered Charge	$I_{SD} = 61A$, $dI_{SD}/dt = 100A/\mu s$		-			nC

FDP3652 / FDB3652 — N-Channel PowerTrench® MOSFET

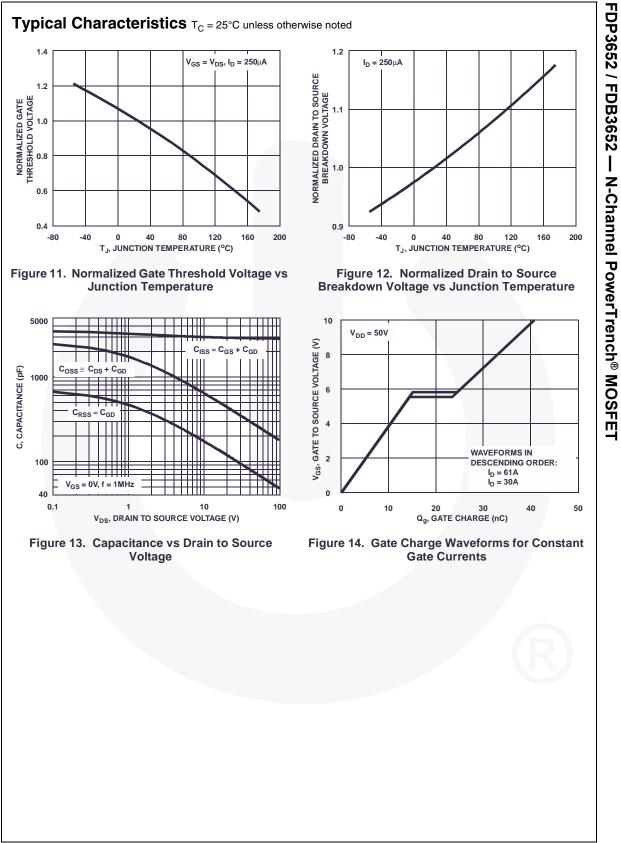
2



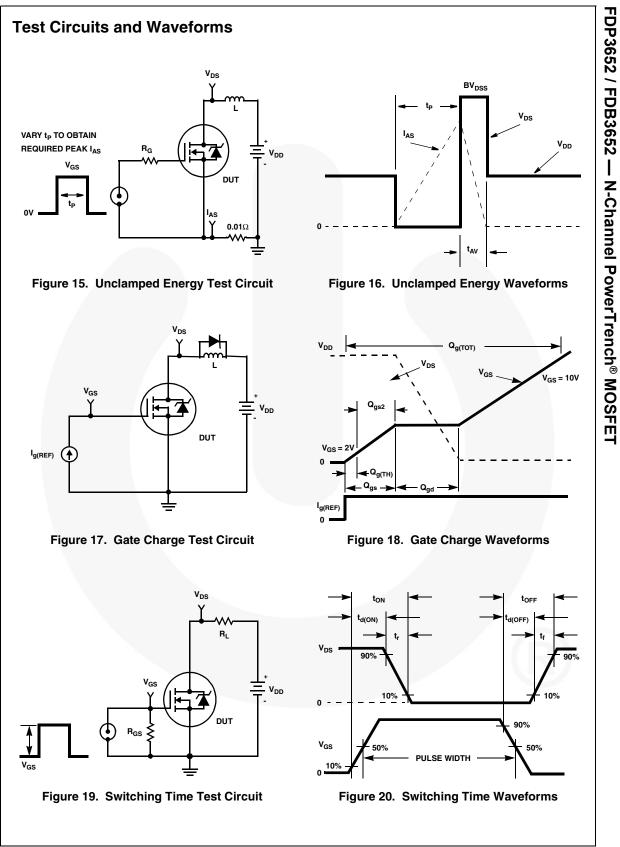
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Thermal Resistance vs. Mounting Pad Area

The maximum rated junction temperature, T_{JM} , and the thermal resistance of the heat dissipating path determines the maximum allowable device power dissipation, P_{DM} , in an application. Therefore the application's ambient temperature, T_A (°C), and thermal resistance $R_{\theta JA}$ (°C/W) must be reviewed to ensure that T_{JM} is never exceeded. Equation 1 mathematically represents the relationship and serves as the basis for establishing the rating of the part.

$$P_{DM} = \frac{(T_{JM} - T_A)}{R_{\theta JA}}$$
(EQ. 1)

In using surface mount devices such as the TO-263 package, the environment in which it is applied will have a significant influence on the part's current and maximum power dissipation ratings. Precise determination of P_{DM} is complex and influenced by many factors:

- Mounting pad area onto which the device is attached and whether there is copper on one side or both sides of the board.
- 2. The number of copper layers and the thickness of the board.
- 3. The use of external heat sinks.
- 4. The use of thermal vias.
- 5. Air flow and board orientation.
- 6. For non steady state applications, the pulse width, the duty cycle and the transient thermal response of the part, the board and the environment they are in.

Fairchild provides thermal information to assist the designer's preliminary application evaluation. Figure 21 defines the $R_{\theta JA}$ for the device as a function of the top copper (component side) area. This is for a horizontally positioned FR-4 board with 1oz copper after 1000 seconds of steady state power with no air flow. This graph provides the necessary information for calculation of the steady state junction temperature or power dissipation. Pulse applications can be evaluated using the Fairchild device Spice thermal model or manually utilizing the normalized maximum transient thermal impedance curve.

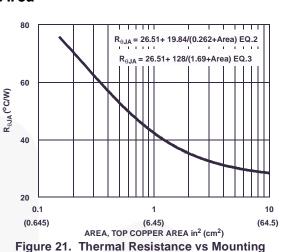
Thermal resistances corresponding to other copper areas can be obtained from Figure 21 or by calculation using Equation 2 or 3. Equation 2 is used for copper area defined in inches square and equation 3 is for area in centimeter square. The area, in square inches or square centimeters is the top copper area including the gate and source pads.

$$R_{\theta JA} = 26.51 + \frac{19.84}{(0.262 + Area)}$$
 (EQ. 2)

$$R_{\theta JA} = 26.51 + \frac{128}{(1.69 + Area)}$$
(EQ. 3)

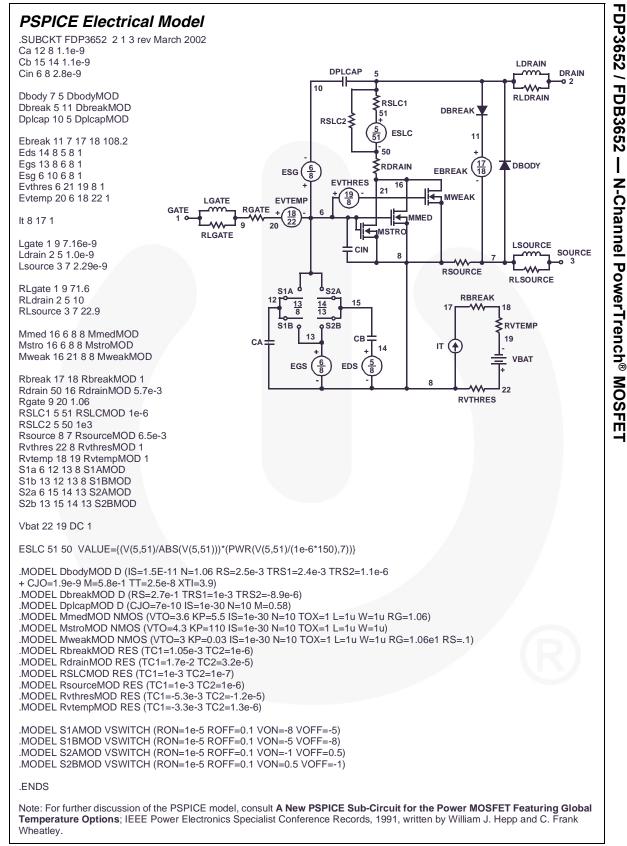
Area in Centimeter Squared

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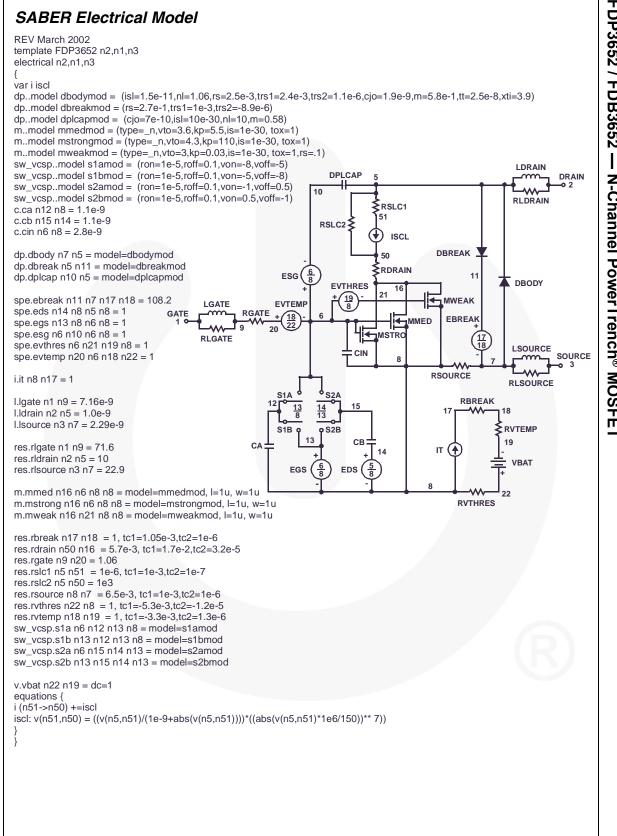
Pad Area

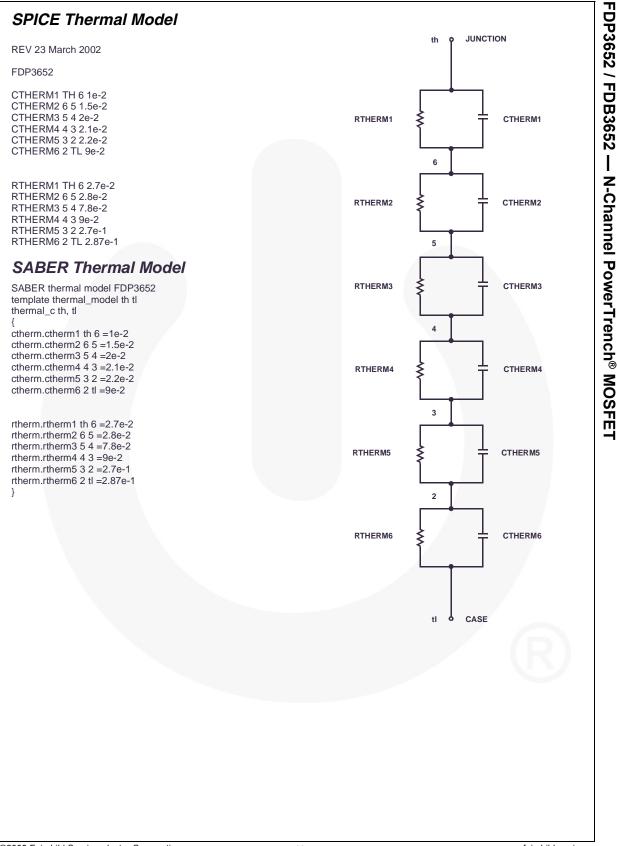
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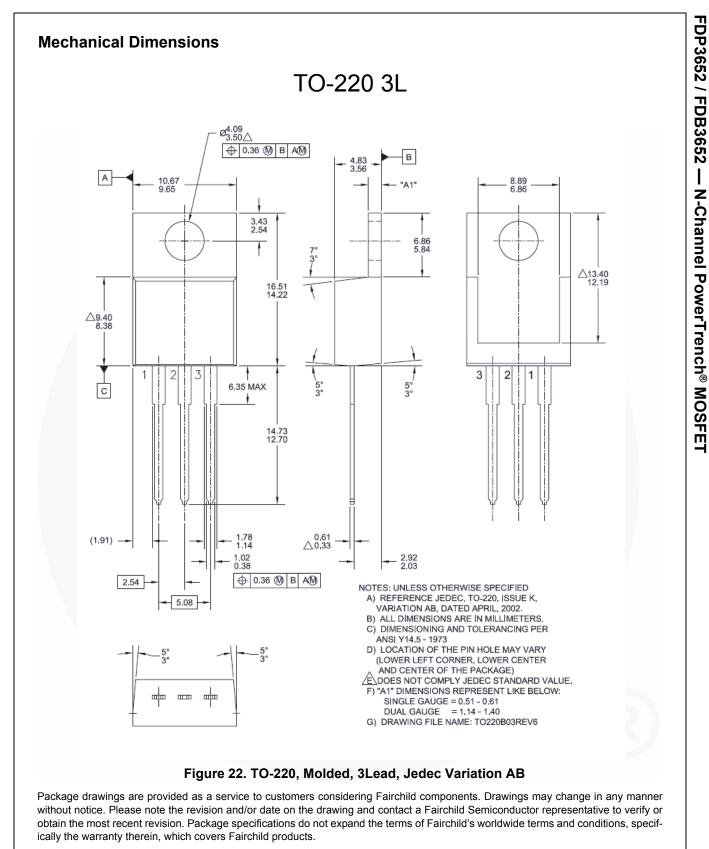


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Dimension in Millimeters

